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Substitute for form 1449/PTO				Complete if Known		
				Application Number	10/581,950-Conf. #8737	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Filing Date	August 18, 2008	
				First Named Inventor	Anderson	
				Art Unit	2822	
	(Use as many sh	eets as	s necessary)	Examiner Name	D. T. Nguyen	
Sheet	1	of	1	Attorney Docket Number	GWS-008	

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number  Number-Kind Code <sup>2</sup> ( <i>if known</i> )	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	A12*	US-5,945,730	08-31-1999	Sicard et al.	
	A13*	US-6,261,944	07-17-2001	Mehta et al.	
	A14*	US-6,507,070	01-14-2003	Shen et al.	
	A15*	US-6,586,323	07-01-2003	Fan et al.	
	A16*	US-6,674,157	01-06-2004	Lang	
	A17*	US-6,861,702	03-01-2005	Kitamura et al.	
	A18*	US-6,936,923	08-30-2005	Lin et al.	
	A19*	US-7,432,595	10-07-2008	Okada	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)				
	B1	WO-2005-057617 A3	06-23-2005	Great Wall Semiconductor		

		NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No. <sup>1</sup>					
	C4	Darwish et al., "Scaling Issues in Lateral Power MOSFETs," Proc. 1998 Intl. Symp. On Power Semiconductor Devices & Ics, pp. 329-332.				
	C5	International Search Report and Written Opinion for PCT/US2004/040698, dated August 8, 2005.				
	C6	International Search Report and Written Opinion for PCT/US2004/40197, mailed November 21, 2008.				
	C7	Pavier et al., "Bi-directional FlipFET™ MOSFETS for Cell Phone Battery Protection Circuits," PCIM 2001.				
	C8	Shen et al., "Lateral Discrete Power MOSFET: Enabling Technology for Next-Generation, MHz-Frequency, High-Density DC/DC Converters," APEC (2004).				
	C9	Sun et al., ""0.35μm, 43 μ $\Omega$ cm $^2$ 6m $\Omega$ Power MOSFET to Power Future Microprocessor," IEEE pp. 77-79 (1999).				
Examiner Signature		Date Considered				

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.

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